Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/812,467	NAIK ET AL.	
Examiner	Art Unit	
Tu M. Nguyen	3748	

SEARCHED						
Class	Subclass	Date	Examiner			
60	274	712006	TMN			
	276	1	1			
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-	286					
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123	295					
	299	7	V			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST Dearch	7/2006	TMN		